


<b>Search Notes</b>  	<b>Application/Control No.</b>  10674159	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN ET AL.
	<b>Examiner</b>  Sean R McGarry	<b>Art Unit</b>  1635

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
WEST, STN, STIC SEQ SRCH, INVENTOR SRCH, reviewed related 11/102,097, provisionals 60/414,457 60/446,377	11/21/08	sm

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/S. R. M./ Primary Examiner.Art Unit 1635
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